

**Notice of References Cited**

Application/Control No.

10/826,299

Applicant(s)/Patent Under  
Reexamination  
LEE, SUNG-HI

Examiner

AKWASI M. SARPONG

Art Unit

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0097418 A1	07-2002	Chang et al.	358/1.13
*	B	US-2003/0037115 A1	02-2003	Tomita et al.	709/206
*	C	US-2004/0001207 A1	01-2004	Nishimura, Takeshi	358/1.2
*	D	US-6,704,122 B2	03-2004	Moro et al.	358/1.9
*	E	US-6,735,641 B1	05-2004	Kobayashi et al.	710/15
*	F	US-6,771,393 B1	08-2004	Honary, Hooman	358/426.01
*	G	US-2004/0268113 A1	12-2004	Rothman et al.	713/002
*	H	US-7,036,076 B2	04-2006	Anwar, Majid	715/255
*	I	US-7,142,321 B2	11-2006	Tomita et al.	358/1.15
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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